

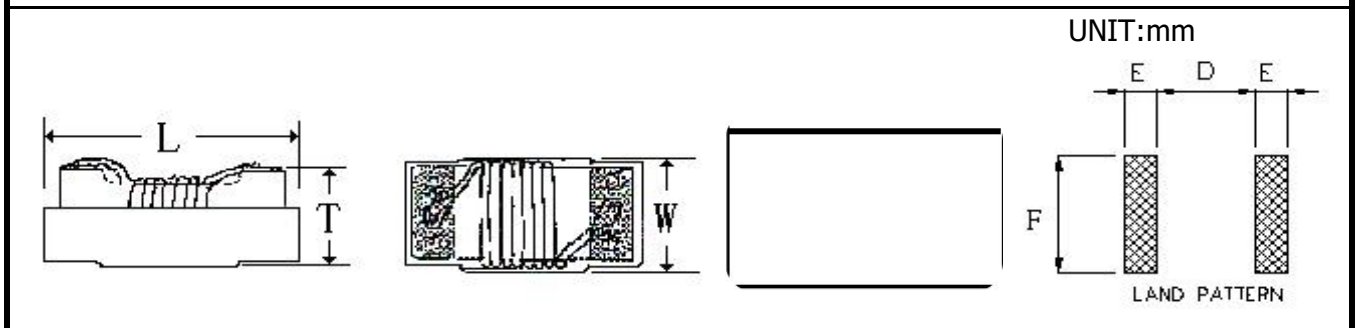


深圳市英拓坤科技有限公司

SHENZHEN YINTK ELECTRONICS CO., LTD

SPECIFICATIONS		DATE	2018年12月5日
CUSTOMER		ITEM	YLFW0805-22K(f)
Q'TY.		PART NO.	-
TEMP	25°C	HUMIDITY	70%

1. SHAPE & DIMENSION



CODE	L	W	T	E	F	D	
DIMENSION	2.29MAX	1.73MAX	1.52MAX	1.02Typ.	1.78Typ.	0.76Typ.	

2. ELECTRICAL CHARACTERISTICS @25°C

ITEM	SPEC. RANGE	TEST CONDITION	TEST INSTRUMENTS
L (μH)	2.20±10%	7.9MHz	HP4286A
Q(品质系数)	12 MIN	7.9MHz	
DCR (Ω)	0.31 MAX		502BC
I _{rms} (mA)	550 MAX		VR116+VR7210
SRF (MHz)	80 MIN		E5071C ENA

3. PART NUMBERING SYSTEM

YLFW
0805
-
22
K
(F)

①
②
③
④
⑤

- ① Product symbol系列代号:
- ② Dimensions 尺寸: Length长 (L) ×Width宽 (W)
- ③ Inductance电感量: 47: 4.7uH; 100: 10μH; R68: 680nH;
- ④ Tolerance允许偏差: J±5%, K±10%,M±20%
- ⑤ Lead free products无铅产品

4. GENERAL SPECIFICATION

- a. Storage temp.: -40°C ~ +85°C, R.H.: 30% ~ 70%, Operating temp.: -40°C ~ +85°C.
- b. Moisture sensitivity level (MSL) 2 (1 year floor life at <30°C/85% relative humidity).
- c. Failures in time(FIT)/Mean Time Between Failures(MTBF) 38 per billion hours/26,315,789 hours, calculated per Telcordia SR-332.

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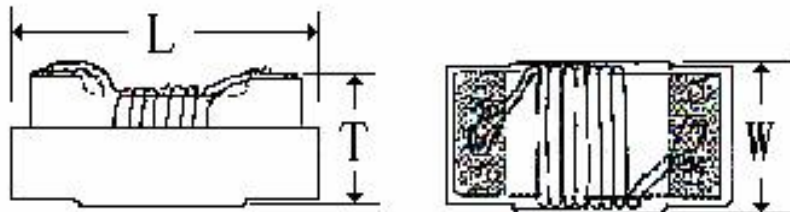
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5. TEST DATA FOR SAMPLES

TEST ITEM	L	Q(品质系数)	DCR	L	W	T	
	(μ H)	(min)	(Ω)	(mm)	(mm)	(mm)	
CON.	7.9MHz	7.9MHz	At 25°C	2.29MAX	1.73MAX	1.52MAX	
SPEC.	2.20 \pm 10%	12 MIN	0.31 MAX				
1	2.23	17.0	0.25	2.16	1.52	1.22	
2	2.16	19.0	0.27	2.14	1.50	1.20	
3	2.20	18.0	0.26	2.15	1.51	1.21	
4	2.18	17.0	0.25	2.16	1.52	1.22	
5	2.22	17.0	0.25	2.16	1.51	1.20	
6	2.21	19.0	0.27	2.14	1.50	1.21	
7	2.20	18.0	0.26	2.15	1.52	1.22	
8	2.20	17.0	0.25	2.16	1.50	1.21	
9	2.19	19.0	0.27	2.14	1.51	1.20	
10	2.21	18.0	0.26	2.15	1.52	1.22	
X	2.20	17.90	0.26	2.15	1.51	1.21	
R	0.07	2.00	0.02	0.02	0.02	0.02	

图示:



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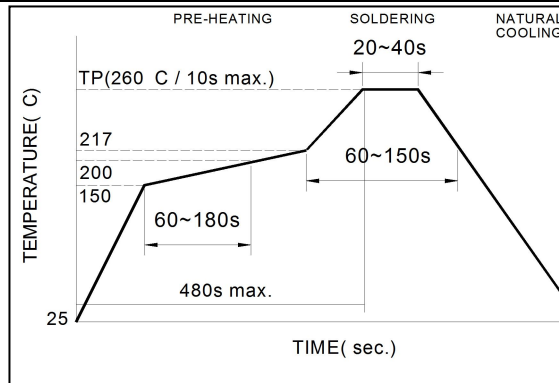
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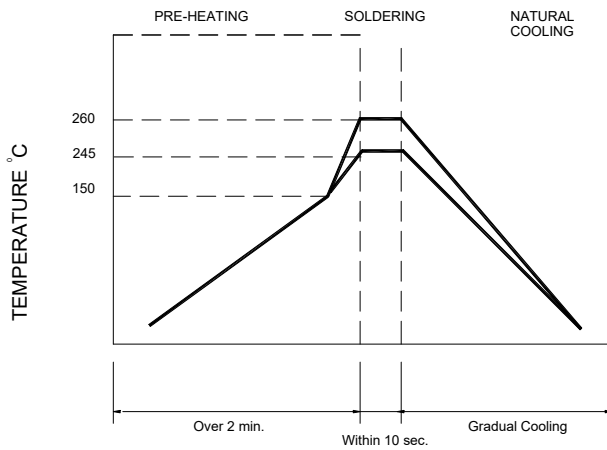
6. SOLDERING CONDITIONS

**Figure 1.
Re-flow
Soldering (Lead
Free)**



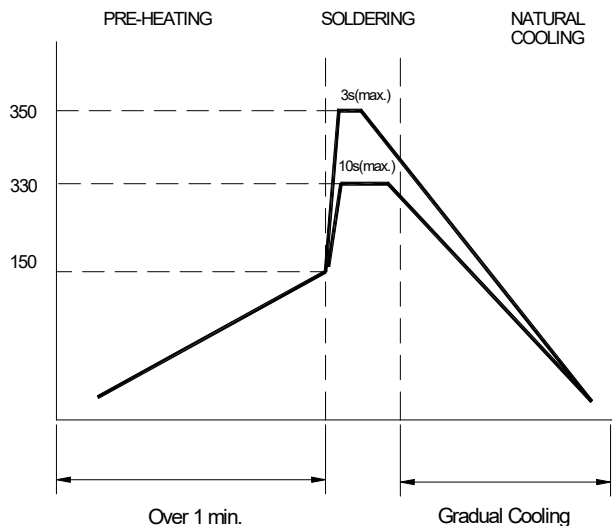
Note:
·Preheat circuit and products to 150°C
·260°C tip temperature (max)

**Figure 2.
Wave Soldering**



Note:
·Never contact the ceramic with the iron tip
·1.0mm tip diameter (max)

**Figure 3.
Hand Soldering**



Note:
·Use a 20 watt soldering iron with tip diameter of 1.0mm
·Limit soldering time to 3 sec.

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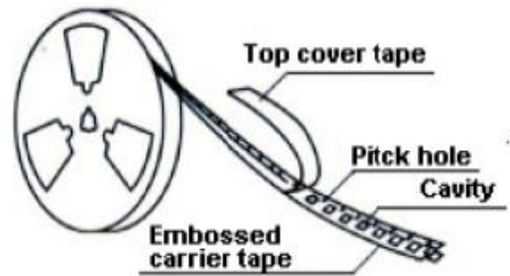
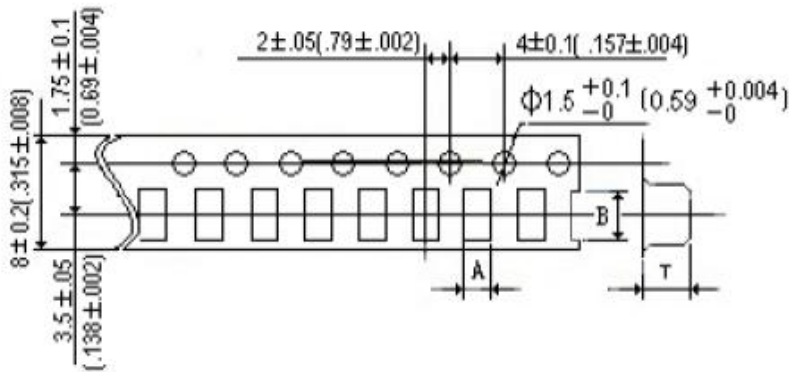
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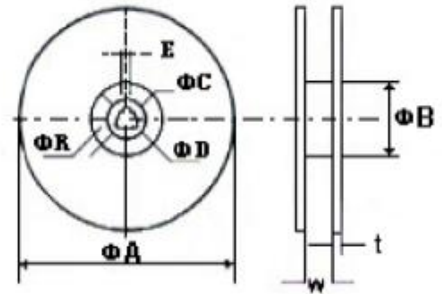
7. PACKAGING(unit: mm)

Tape

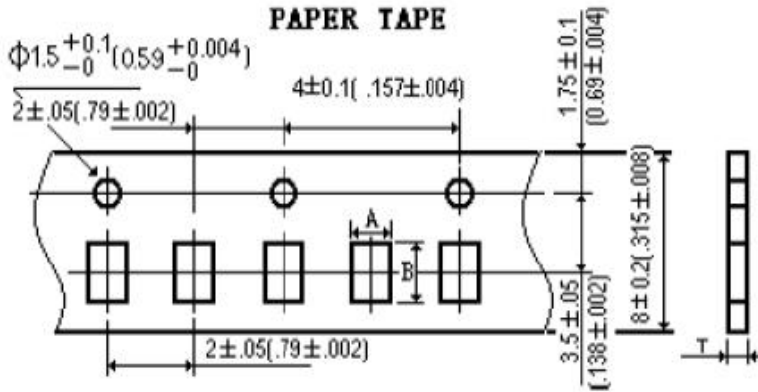
POLYSTYRENE TAPE



Reel Dimensions



PAPER TAPE



		A	B	T
纸带	0402	0.74	1.23	0.60
	0603	1.15	1.83	0.95
胶带	0805	1.85	2.40	1.45
	1008	2.73	2.90	2.34
	1210	2.96	3.60	2.40

unit	ΦA	ΦB	ΦC	ΦD	E	W	t	R
mm	178	60	13	21	2	10	2	1
	330	75	13	23	2	12	2	1

包装数量(PACKAGING QUANTITY)

规格	0402	0603	0805	1008	1210	
数量(pcs)	10000	4000	3000	2000	2000	

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8. 1 RELIABILITY TEST

TEST ITEM	SPECIFICATION	TEST CONDITION
Rating current	According to product specifications	Current sources:33010D
Inductance	According to product specifications	Test Frequency:0.252~250MHz Test Equipment:HP4291A、HP4286A、HP4287A、HP4284A Test Fixture:16193Aor16334A
Q	According to product specifications	Test Frequency:0.252~1500MHz Test Equipment:HP4291A、HP4286A、HP4287A、Test Fixture:16193Aor16334A
RDC	According to product specifications	Test Equipment:HP4263B
SRF	According to product specifications	Test Equipment:HP4291A Test Fixture:16193A
Solderability	The metalized area must have more then 90%of solder coverage	Soldering Temp:230±5°C Dipping time:5±1S
Resistance to soldering heat	No evidence of mechanical damage The mealized arer must have more then 75%of solder coverage Inductance change,less than±5% Q change less than±10%	Soldering Temp:260±5°C Dipping time:10±1S
Thermal Shock	No evidence of mechanical damage, Inductance change less than±5%, Q change less than±10%	A cycle contain:Step1:-40°C , 30Min Step 2:85°C , 30Min Cycle Times:10

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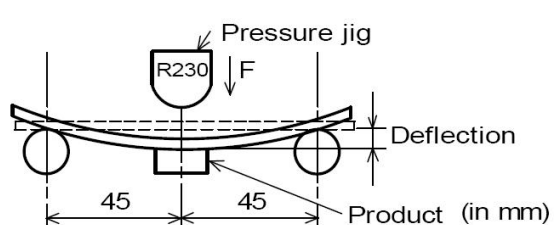


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TEMP	25°C	HUMIDITY	70%

8.2 RELIABILITY TEST

TEST ITEM	SPECIFICATION	TEST CONDITION
High Temperature Storage	No evidence of mechanical damage, Inductance change less than±5%, Q change less than±10%	Test Temperature:125±2°C (Ceramic core)85±2°C (Ferrite core) Test Time:96±2Hours
Low Temperature Storage	No evidence of mechanical damage, Inductance change less than±5%, Q change less than±10%	Test Temperature:-40±2°C Test Time:96±2Hours
Moisture Resistance	No evidence of mechanical damage, Inductance change less than±5%, Q change less than±10%	Test Temperature:50±2°C Test Time:100Hours relative humidity:90~95%
Vibration	No evidence of mechanical damage, Inductance change less than±5%, Q change less than±10%	Amplitude:1.5mm X、Y、Z each direction for 1Hour and 45min Frequency range:10~55~10Hz(min)
Component Adhesion	No evidence of mechanical damage No evidence of peel off or broken Keep continuity of Winding	Force:2Kg Test Time:5±1sec
Resistance to bend	No evidence of mechanical damage	Camber:20mm Test Board:Glass-Epoxy board Thickness:8mm 
Life	No evidence of mechanical damage, Inductance change less than±5%, Q change less than±10%	Test Temperature:85±2°C Test Time:1000Hours with rating current

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